

TM25G04GD
N+P-Channel Enhancement Mode Mosfet
General Description

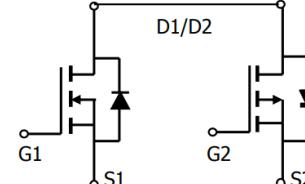
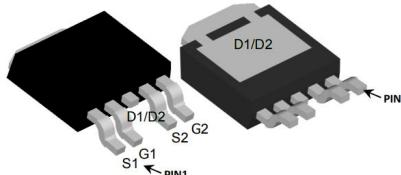
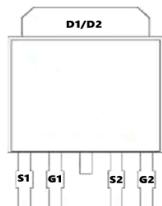
- Low $R_{DS(ON)}$
- RoHS and Halogen-Free Compliant

Applications

- Load switch
- PWM

General Features
N Channel
 $V_{DS} = 40V$ $I_D = 25A$
 $R_{DS(ON)} = 17m\Omega$ (typ.) @ $V_{GS} = 10V$
P Channel
 $V_{DS} = -40V$ $I_D = -23A$
 $R_{DS(ON)} = 35m\Omega$ (typ.) @ $V_{GS} = -10V$

100% UIS Tested

100% R_g Tested
GD:TO-252-4L


Marking: 25G04 OR 4012

Absolute Maximum Ratings ($T_A = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	N Channel	P Channel	Unit	
Common Ratings					
V_{DSS}	Drain-Source Voltage	40	-40	V	
V_{GSS}	Gate-Source Voltage	± 20	± 20		
T_J	Maximum Junction Temperature	150		$^\circ C$	
T_{STG}	Storage Temperature Range	-55 to 150			
I_S	Diode Continuous Forward Current	$T_C = 25^\circ C$	10	A	
I_D	Continuous Drain Current	$T_C = 25^\circ C$	25		
		$T_C = 100^\circ C$	19.2		
P_D	Maximum Power Dissipation	$T_C = 25^\circ C$	32.9	W	
		$T_C = 100^\circ C$	13.2		
$R_{\theta JC}$	Thermal Resistance-Junction to Case	3.8	3.8	$^\circ C/W$	
I_{DM}^a	Pulsed Drain Current	$T_C = 25^\circ C$	80*	A	
$R_{\theta JA}$	Thermal Resistance-Junction to Ambient	$t \leq 10s$	25	$^\circ C/W$	
		Steady State ^c	60		
I_{AS}^b	Avalanche Current, Single pulse	$L=0.5mH$	10	-9	A
E_{AS}^b	Avalanche Energy, Single pulse	$L=0.5mH$	25	25	mJ

Note * : Limited by package.

Note a : Pulse width limited by max. junction temperature.

Note b : UIS tested and pulse width limited by maximum junction temperature $150^\circ C$ (initial temperature $T_j=25^\circ C$).Note c : Surface Mounted on 1in² pad area, $t = 999sec$.

N Channel Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

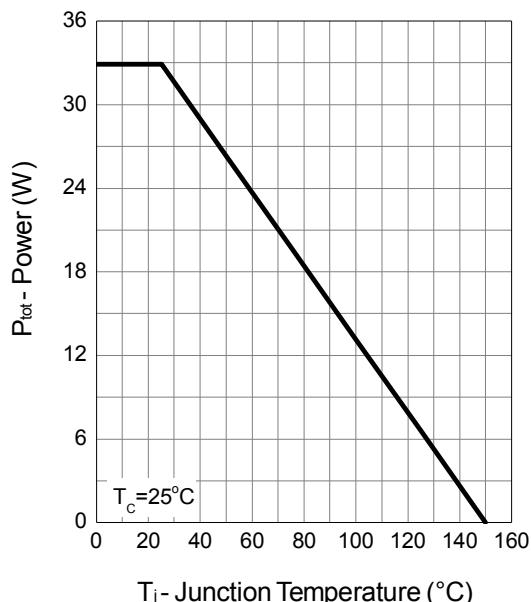
Symbol	Parameter	Test Conditions	N Channel			Unit
			Min.	Typ.	Max.	
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{V}_{\text{GS}}=0\text{V}, \text{I}_{\text{DS}}=250\mu\text{A}$	40	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=32\text{V}, \text{V}_{\text{GS}}=0\text{V}$	-	-	1	μA
		$\text{T}_J=85^\circ\text{C}$	-	-	30	
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{DS}}=250\mu\text{A}$	1.5	2	2.5	V
I_{GSS}	Gate Leakage Current	$\text{V}_{\text{GS}}=\pm20\text{V}, \text{V}_{\text{DS}}=0\text{V}$	-	-	± 100	nA
$\text{R}_{\text{DS(ON)}}^{\text{d}}$	Drain-Source On-state Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{DS}}=10\text{A}$	-	17	24	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{DS}}=5\text{A}$	-	25	37	
Diode Characteristics						
$\text{V}_{\text{SD}}^{\text{d}}$	Diode Forward Voltage	$\text{I}_{\text{SD}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$	-	0.75	1.1	V
t_{rr}	Reverse Recovery Time	$\text{I}_{\text{DS}}=10\text{A}, \frac{d\text{I}_{\text{SD}}}{dt}=100\text{A}/\mu\text{s}$	-	13	-	ns
Q_{rr}	Reverse Recovery Charge		-	8.7	-	nC
Dynamic Characteristics ^e						
R_{G}	Gate Resistance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=0\text{V}, \text{F}=1\text{MHz}$	-	2.5	-	Ω
C_{iss}	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=20\text{V}, \text{Frequency}=1.0\text{MHz}$	-	815	-	pF
C_{oss}	Output Capacitance		-	95	-	
C_{rss}	Reverse Transfer Capacitance		-	60	-	
$\text{t}_{\text{d(ON)}}$	Turn-on Delay Time	$\text{V}_{\text{DD}}=20\text{V}, \text{R}_{\text{L}}=20\Omega, \text{I}_{\text{DS}}=1\text{A}, \text{V}_{\text{GEN}}=10\text{V}, \text{R}_{\text{G}}=6\Omega$	-	7.8	-	ns
t_{r}	Turn-on Rise Time		-	6.9	-	
$\text{t}_{\text{d(OFF)}}$	Turn-off Delay Time		-	22.4	-	
t_{f}	Turn-off Fall Time		-	4.8	-	
Gate Charge Characteristics ^e						
Q_{g}	Total Gate Charge	$\text{V}_{\text{DS}}=20\text{V}, \text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{DS}}=10\text{A}$	-	15.7	22	nC
Q_{g}	Total Gate Charge	$\text{V}_{\text{DS}}=20\text{V}, \text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{DS}}=10\text{A}$	-	7.5	10.5	
Q_{gth}	Threshold Gate Charge		-	1.85	-	
Q_{gs}	Gate-Source Charge		-	3.24	-	
Q_{gd}	Gate-Drain Charge		-	2.75	-	

Note d : Pulse test ; pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.

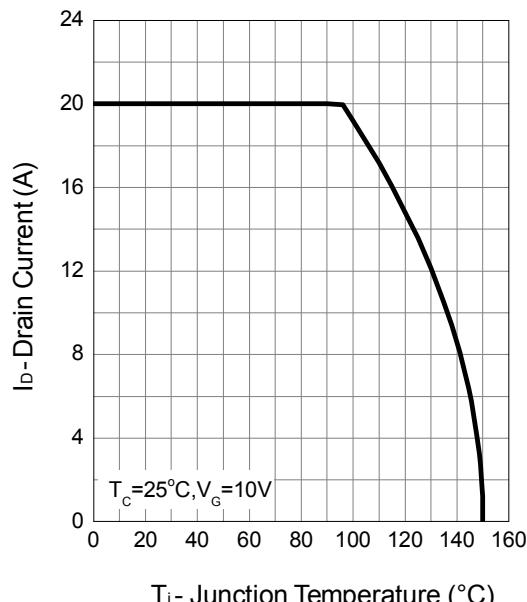
Note e : Guaranteed by design, not subject to production testing.

N Channel Typical Operating Characteristics

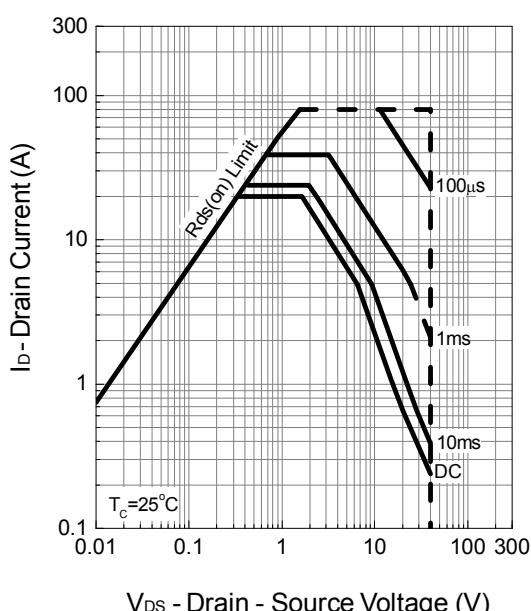
Power Dissipation



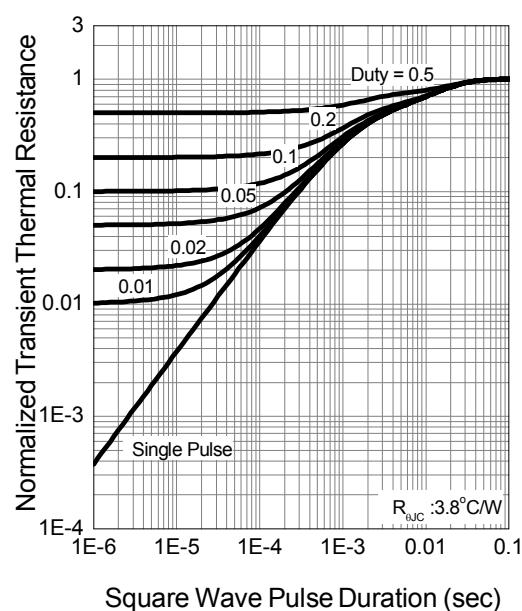
Drain Current



Safe Operation Area



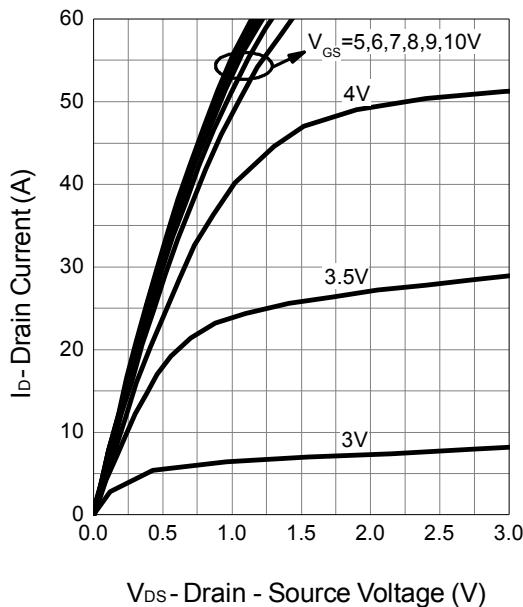
Thermal Transient Impedance



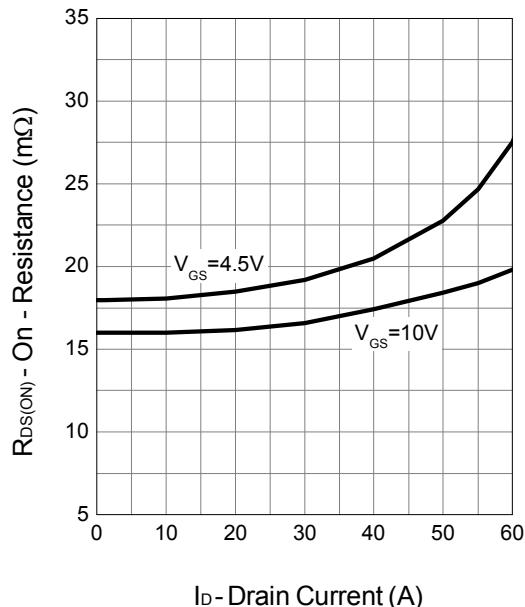
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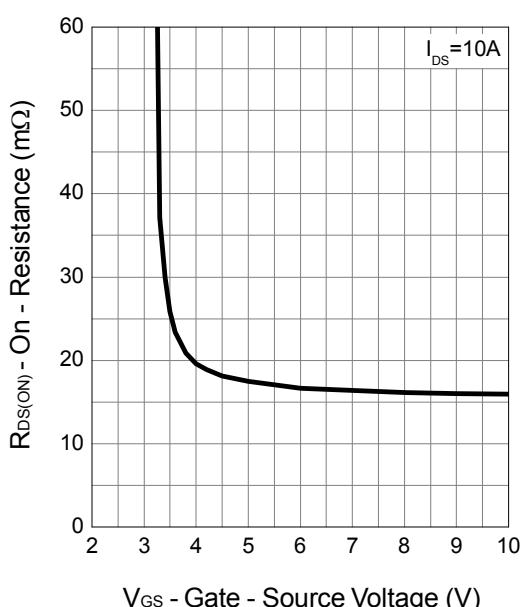
Output Characteristics



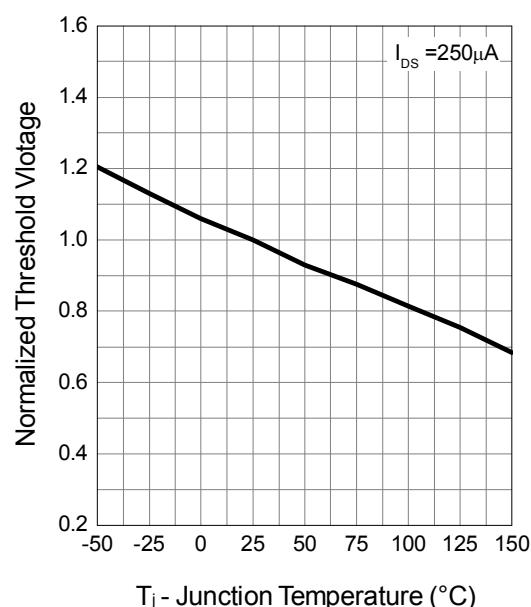
Drain-Source On Resistance



Gate-Source On Resistance

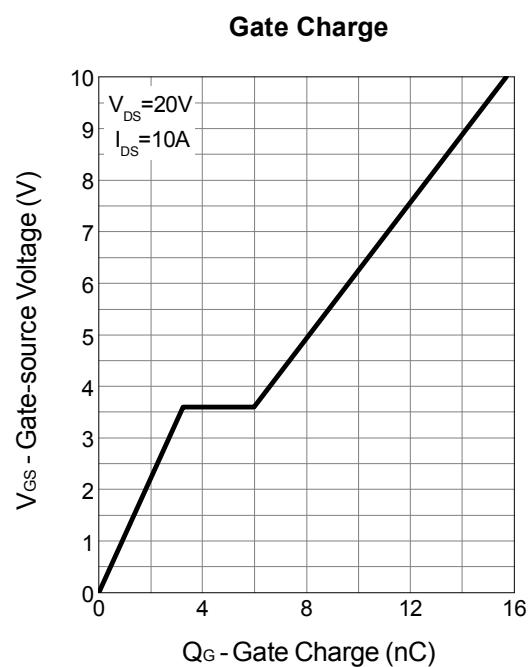
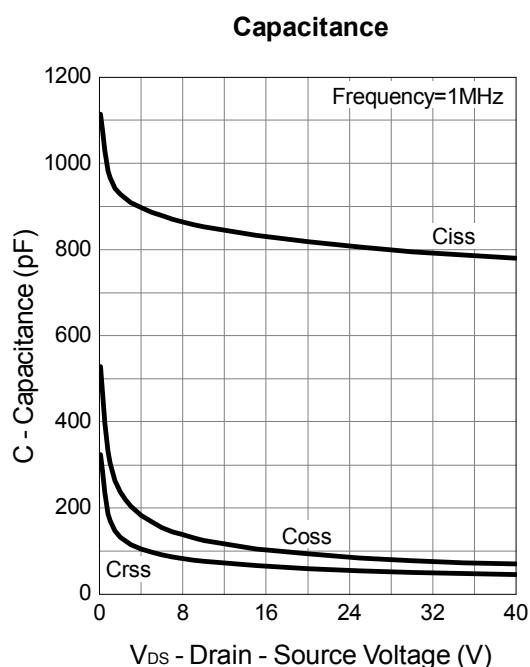
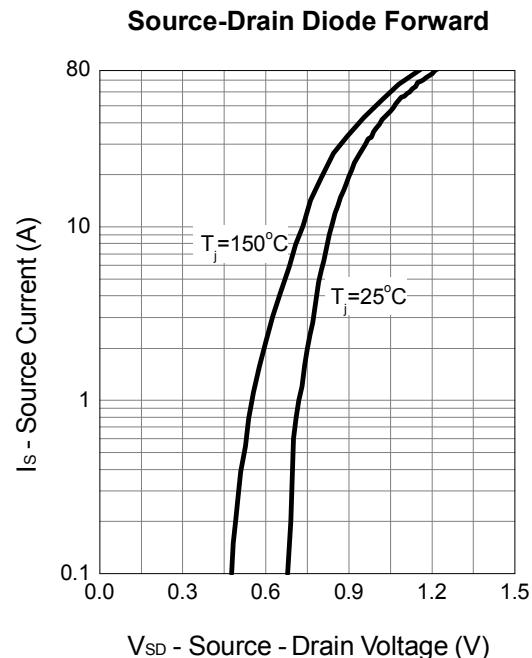
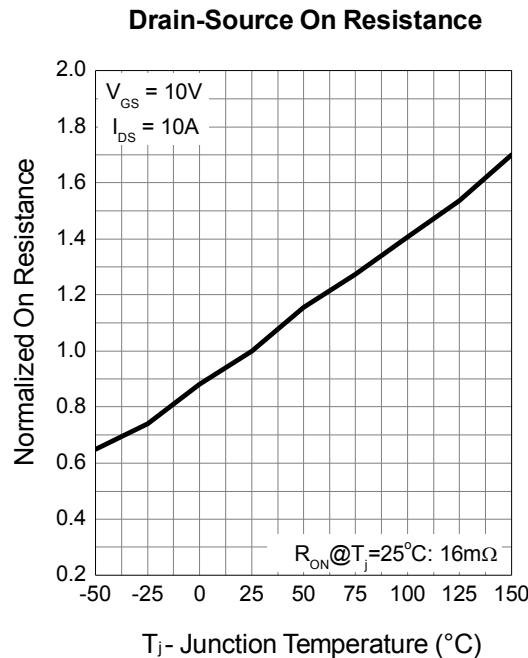


Gate Threshold Voltage



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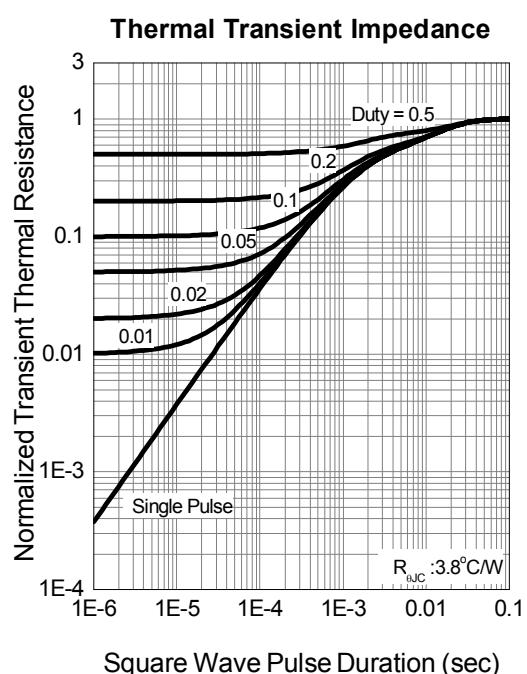
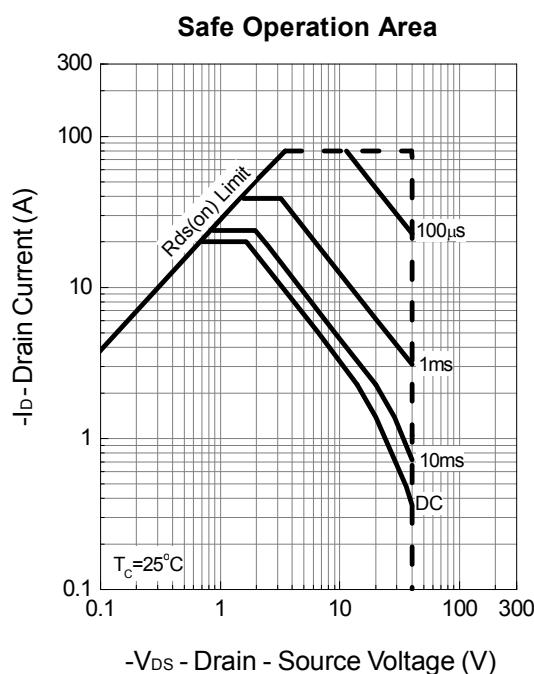
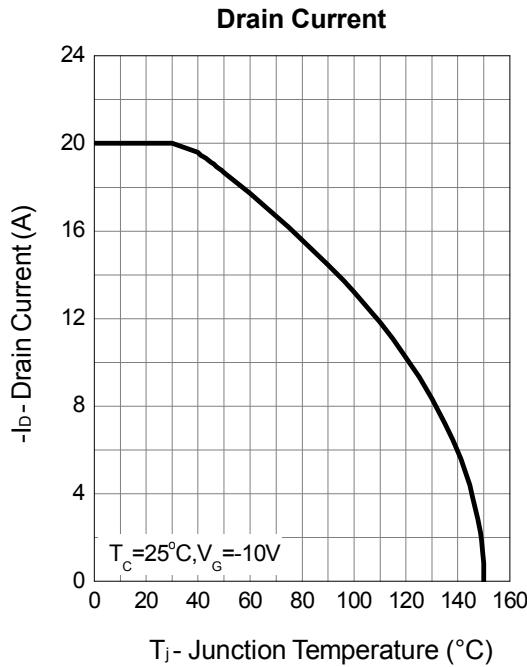
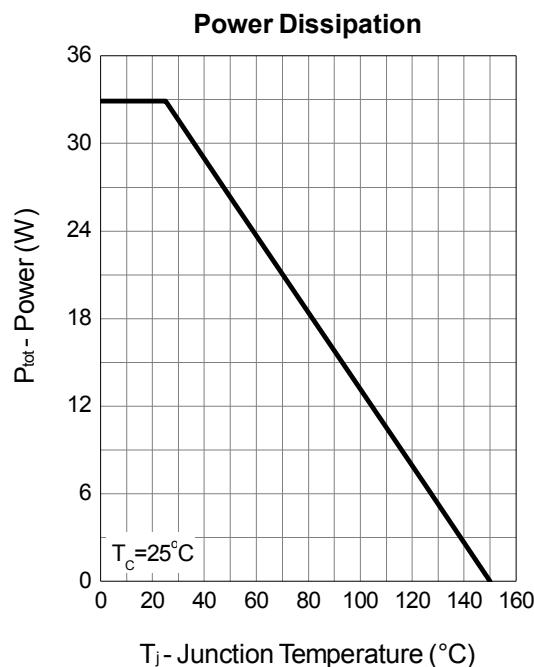
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P Channel Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

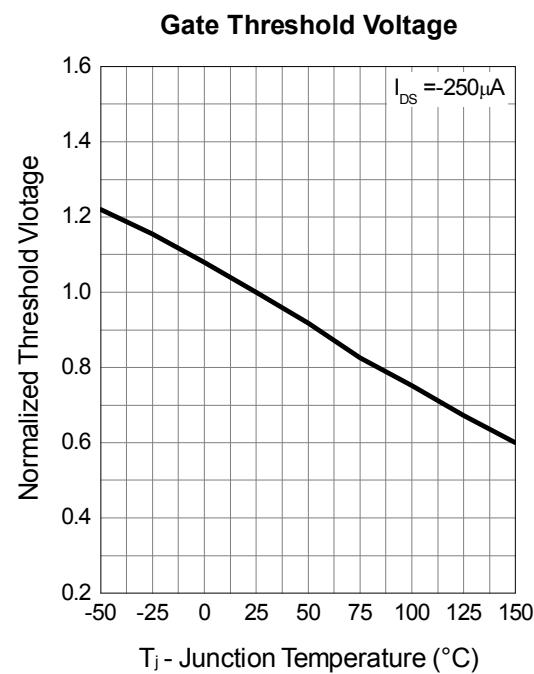
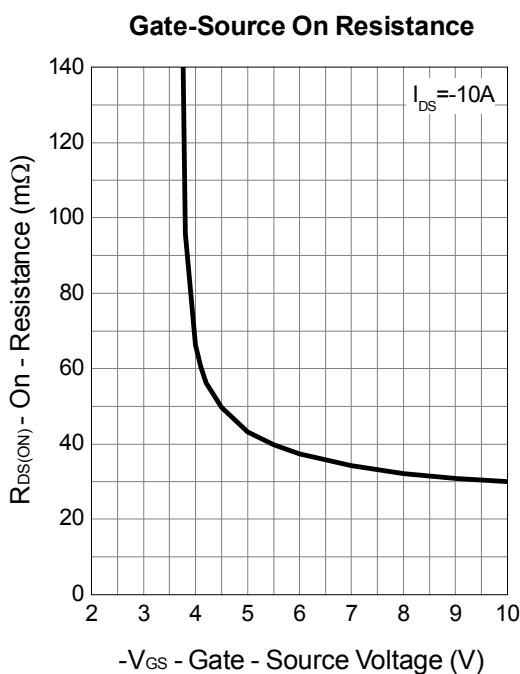
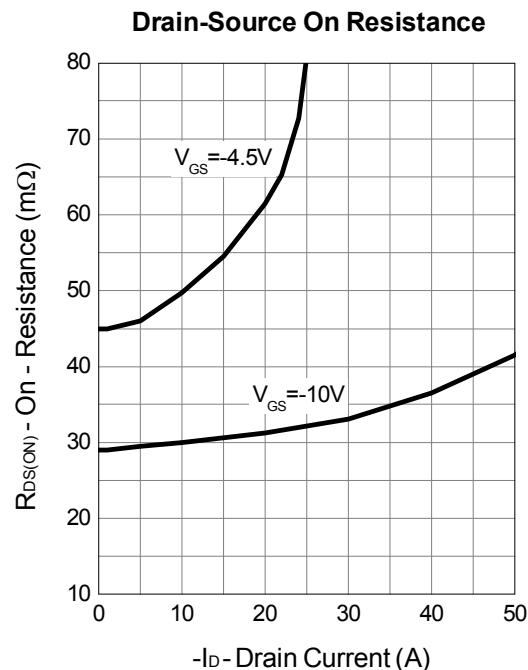
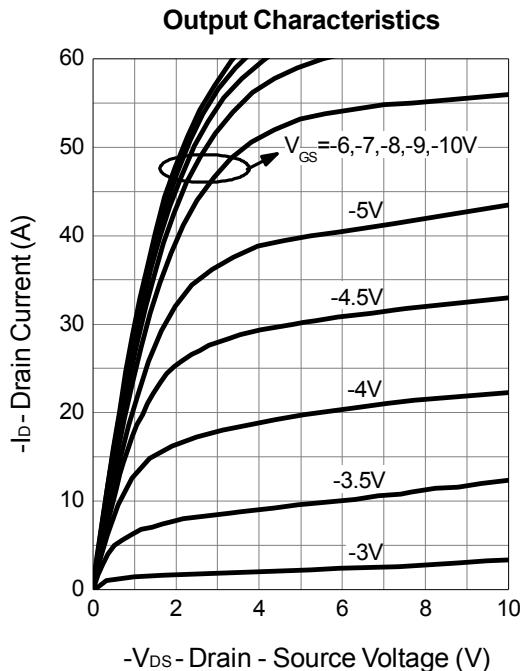
Symbol	Parameter	Test Conditions	P Channel			Unit
			Min.	Typ.	Max.	
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{DS}}=-250\mu\text{A}$	-40	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=-32\text{V}, V_{\text{GS}}=0\text{V}$ $T_J=85^\circ\text{C}$	-	-	-1	μA
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{DS}}=-250\mu\text{A}$	-1.5	-2	-2.5	V
I_{GSS}	Gate Leakage Current	$V_{\text{GS}}=\pm20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	±100	nA
$R_{\text{DS(ON)}}^d$	Drain-Source On-state Resistance	$V_{\text{GS}}=-10\text{V}, I_{\text{DS}}=-10\text{A}$	-	35	46	$\text{m}\Omega$
		$V_{\text{GS}}=-4.5\text{V}, I_{\text{DS}}=-5\text{A}$	-	47	57	
Diode Characteristics						
V_{SD}^d	Diode Forward Voltage	$I_{\text{SD}}=-1\text{A}, V_{\text{GS}}=0\text{V}$	-	-0.75	-1	V
t_{rr}	Reverse Recovery Time	$I_{\text{DS}}=-10\text{A}, dI_{\text{SD}}/dt=100\text{A}/\mu\text{s}$	-	15	-	ns
Q_{rr}	Reverse Recovery Charge		-	8	-	nC
Dynamic Characteristics ^e						
R_{G}	Gate Resistance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=0\text{V}, F=1\text{MHz}$	-	8	-	Ω
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=-20\text{V}, \text{Frequency}=1.0\text{MHz}$	-	668	-	pF
C_{oss}	Output Capacitance		-	98	-	
C_{rss}	Reverse Transfer Capacitance		-	72	-	
$t_{\text{d(ON)}}$	Turn-on Delay Time	$V_{\text{DD}}=-20\text{V}, R_{\text{L}}=20\Omega, I_{\text{DS}}=-1\text{A}, V_{\text{GEN}}=-10\text{V}, R_{\text{G}}=6\Omega$	-	8.7	-	ns
t_{r}	Turn-on Rise Time		-	7	-	
$t_{\text{d(OFF)}}$	Turn-off Delay Time		-	31	-	
t_{f}	Turn-off Fall Time		-	17	-	
Gate Charge Characteristics ^e						
Q_{g}	Total Gate Charge	$V_{\text{DS}}=-20\text{V}, V_{\text{GS}}=-10\text{V}, I_{\text{DS}}=-10\text{A}$	-	15	-	nC
Q_{g}	Total Gate Charge	$V_{\text{DS}}=-20\text{V}, V_{\text{GS}}=-4.5\text{V}, I_{\text{DS}}=-10\text{A}$	-	7.5	-	
Q_{gth}	Threshold Gate Charge		-	1.4	-	
Q_{gs}	Gate-Source Charge		-	2.4	-	
Q_{gd}	Gate-Drain Charge		-	3.5	-	

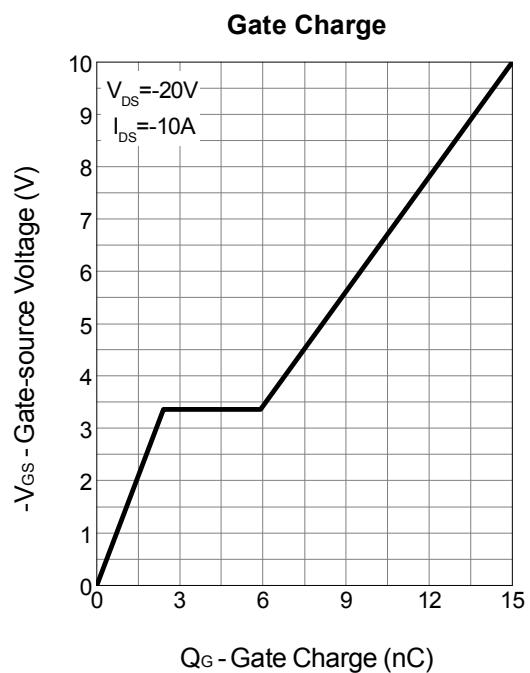
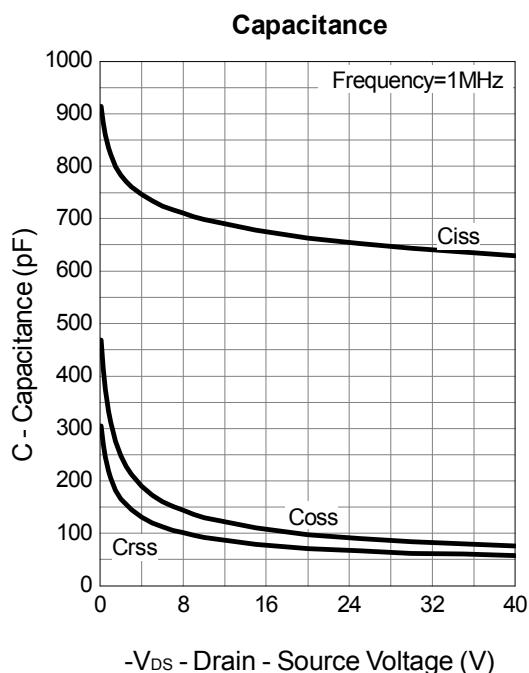
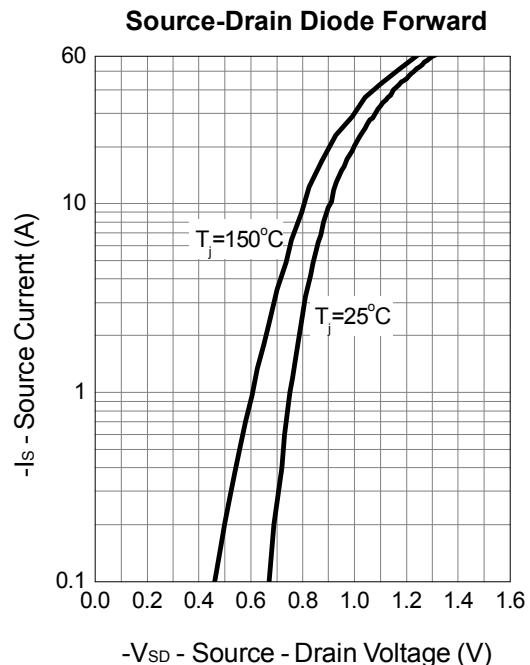
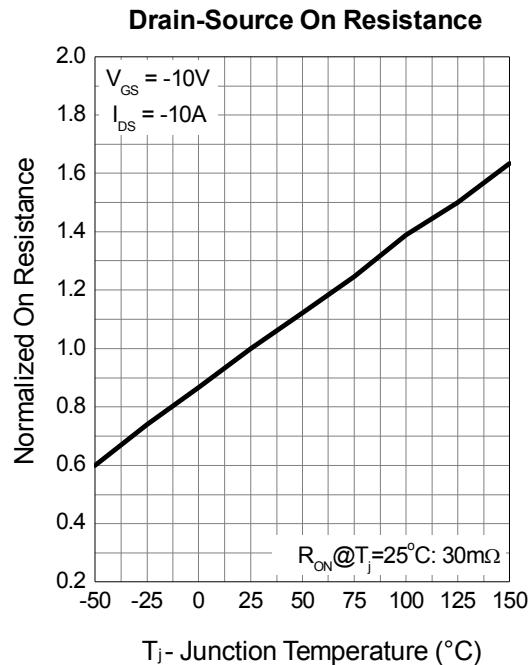
Note d : Pulse test; pulse width $\leq300\mu\text{s}$, duty cycle $\leq2\%$.

Note e : Guaranteed by design, not subject to production testing.

P Channel Typical Operating Characteristics







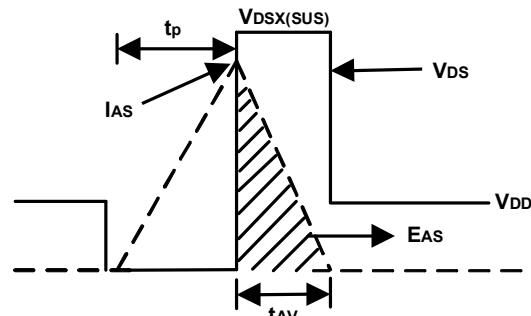
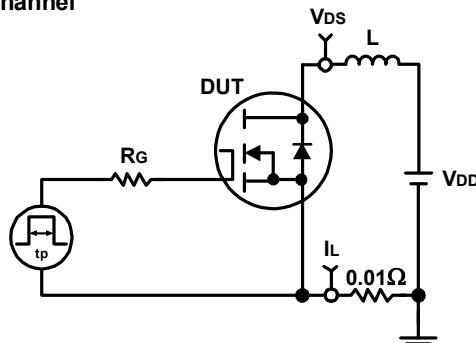


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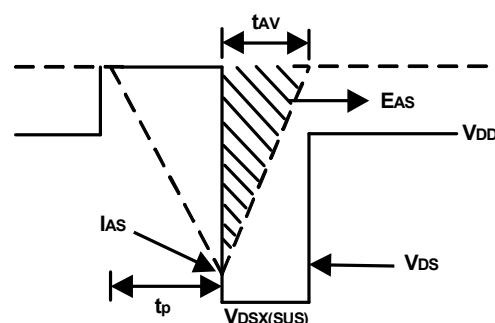
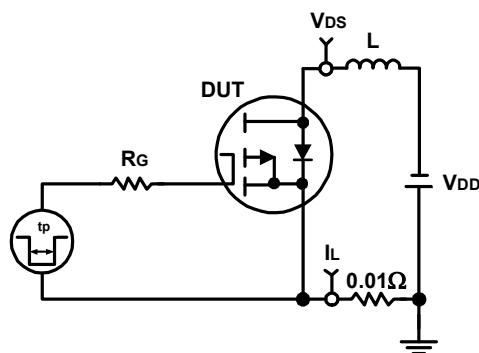
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Avalanche Test Circuit and Waveforms

N Channel

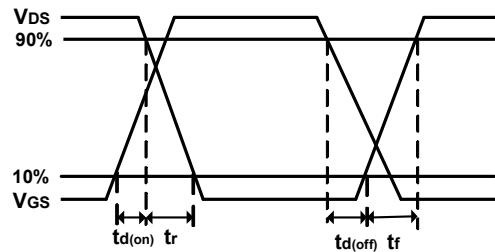
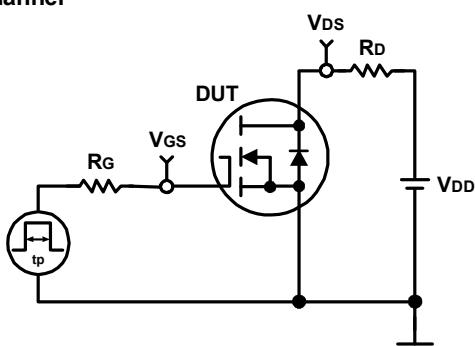


P Channel

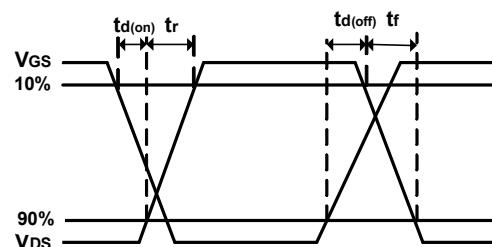
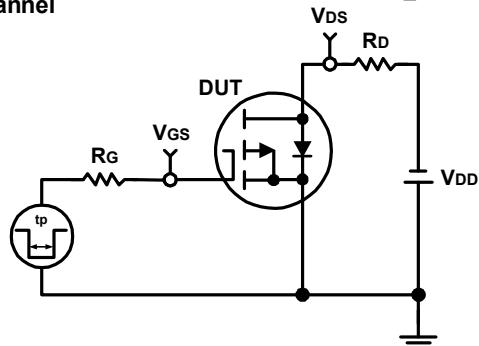


Switching Time Test Circuit and Waveforms

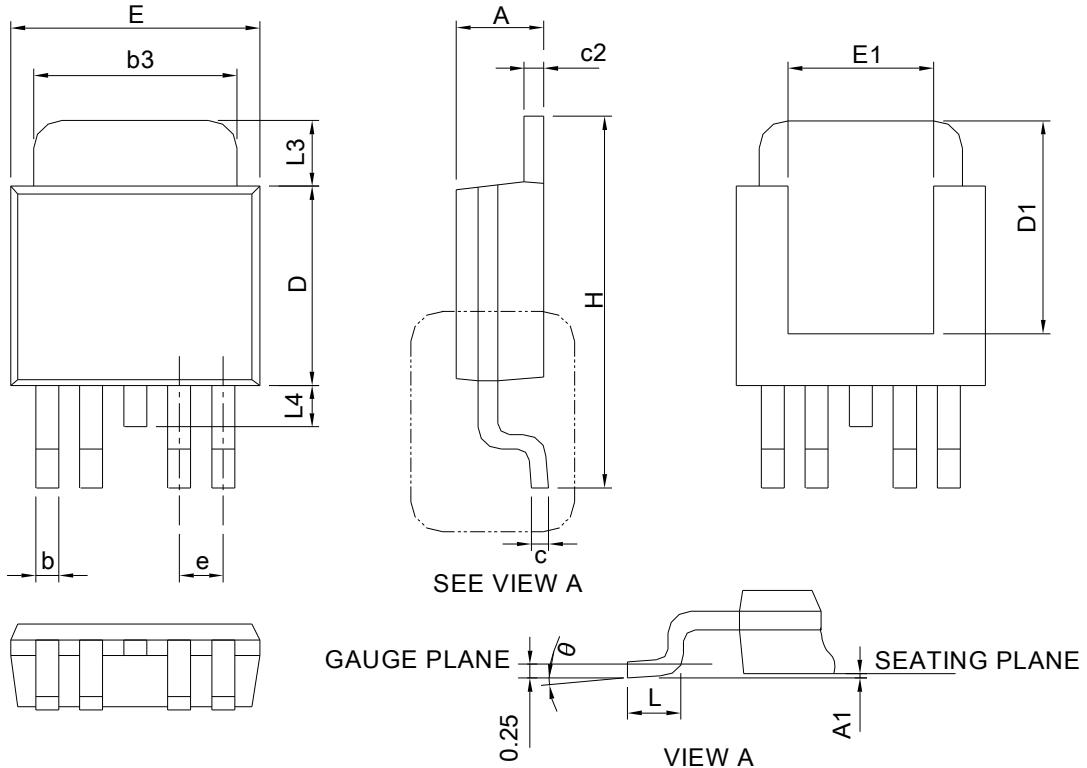
N Channel



P Channel



Package Mechanical Data: TO-252-4L



ITEM	TO-252-4			
	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	2.18	2.39	0.086	0.094
A1	-	0.2	-	0.008
b	0.50	0.71	0.020	0.028
b3	4.32	5.46	0.170	0.215
c	0.46	0.61	0.018	0.024
c2	0.46	0.89	0.018	0.035
D	5.33	6.22	0.210	0.245
D1	4.57	6.00	0.180	0.236
E	6.35	6.73	0.250	0.265
E1	3.81	6.00	0.150	0.236
e	1.30 BSC		0.051 BSC	
H	9.40	10.41	0.370	0.410
L	1.40	1.78	0.055	0.070
L3	0.89	2.03	0.035	0.080
L4	-	1.02	-	0.040
θ	0°	8°	0°	8°

RECOMMENDED LAND PATTERN

